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Docket Number (Optional)	Application Number
P 6079-11005	09/837,887
Applicant(s): Voorakaranam et al.	
Filing Date: April 18, 2001	Group Art Unit: ~~2858~~ 2857

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KW		6,114,858	9/5/00	Kasten	324	616	

RECEIVED JUL 1 5 2002 Technology Center 2100

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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES	Translation NO

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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-A820
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